NEX QC

Energy Dispersive X-ray Fluorescence

Low-cost EDXRF Elemental Analyzer

Rigaku

Applied Rigaku Technologies

NEX QC Delivers Superior Performance in a Rugged Package

Energy dispersive X-ray fluorescence (EDXRF) is a routinely used analytical technique for the qualitative and quantitative determination of major and minor atomic elements in a wide variety of sample types. The heart of its versatility stems from the ability to provide rapid, non-destructive, multi-element analyses — from low parts-per-million (ppm) levels to high weight percent (wt%) concentrations — for elements from sodium ($_{11}$Na) through uranium ($_{92}$U). The versatile Rigaku NEX QC EDXRF spectrometer delivers routine elemental measurements across a diverse range of matrices — from homogeneous liquids of any viscosity to solids, thin films, alloys, slurries, powders and pastes.

Elemental Analysis in the Field, Plant or Lab

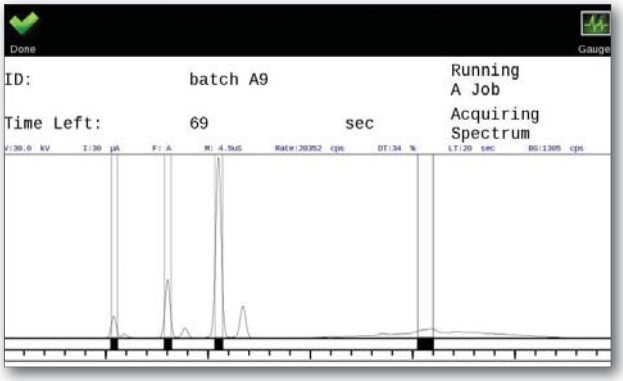
Especially designed and engineered for heavy industrial use, whether on the plant floor or in remote field environments, the superior analytical power, flexibility and ease-of-use of the NEX QC adds to its broad appeal for an ever expanding range of applications, including exploration, research, RoHS inspection, and education, as well as industrial and production monitoring applications. Whether the need is basic quality control (QC) or its more sophisticated variants — such as analytical quality control (AQC), quality assurance (QA) or statistical process control like Six Sigma — the NEX QC is the reliable choice for routine elemental analysis.

Next Generation Low-cost EDXRF Elemental Analyzer

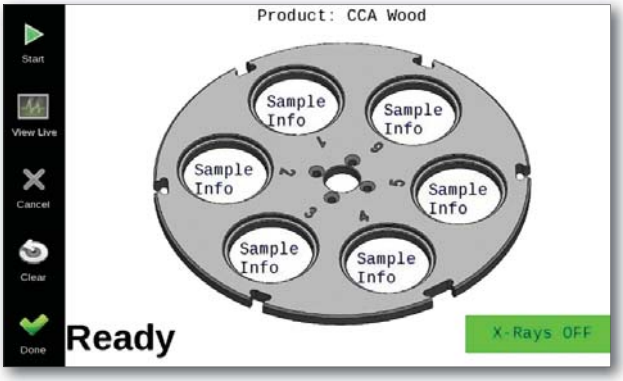
Intuitive Software with Touchscreen Interface

Availability of hardened high-resolution touchscreen displays has allowed Rigaku to redefine the user interface experience for the 21st century. Membrane keyboards and primitive displays are now a thing of the past. Operating the NEX QC elemental analyzer is a familiar experience, with finger selectable icons guiding users through routine analysis operations. Touchscreen interface technology lowers the cost of ownership because it simplifies operator training and reduces the potential for operator error.

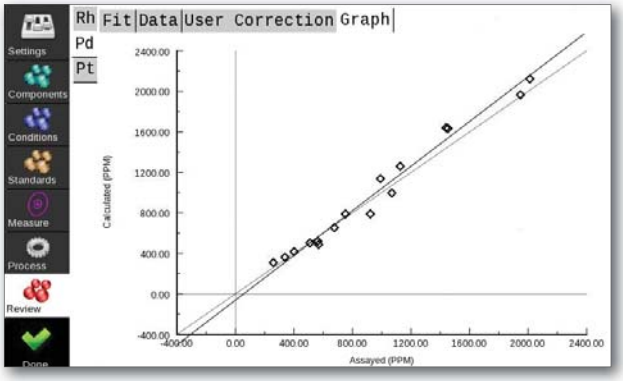
Graphical top level menu allows the operator to select the desired analysis with the touch of an icon



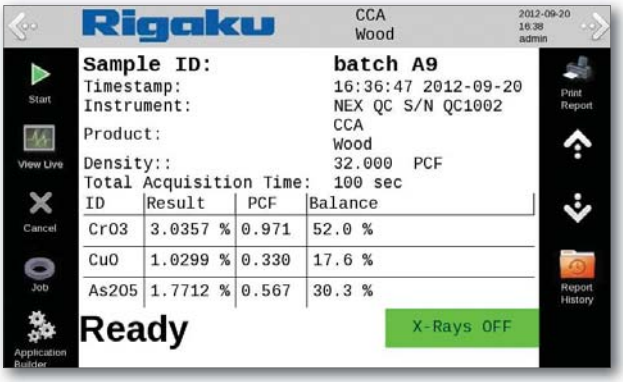
Live spectrum acquisition with the NEX QC showing Cr, Cu and As peaks from a treated lumber sample



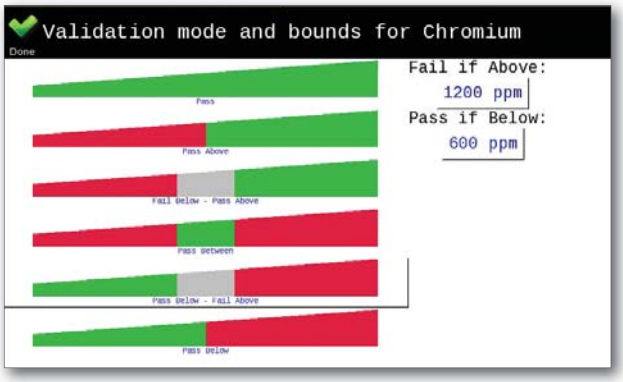
Next, enter the sample identification for each sample tray position and touch the "start" icon



Calibration curves and statistics are accessible with a familiar smartphone style interface



Analytical results, spectra and instrument status are icon selectable with the touch of a finger



Validation mode may be easily set up to afford automatic pass/fail interpretation of analytical results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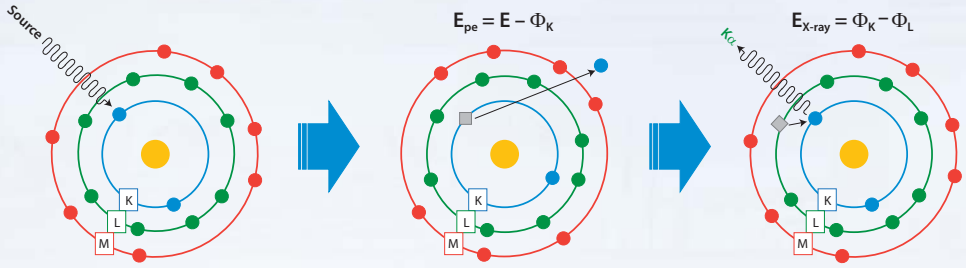
How XRF Works

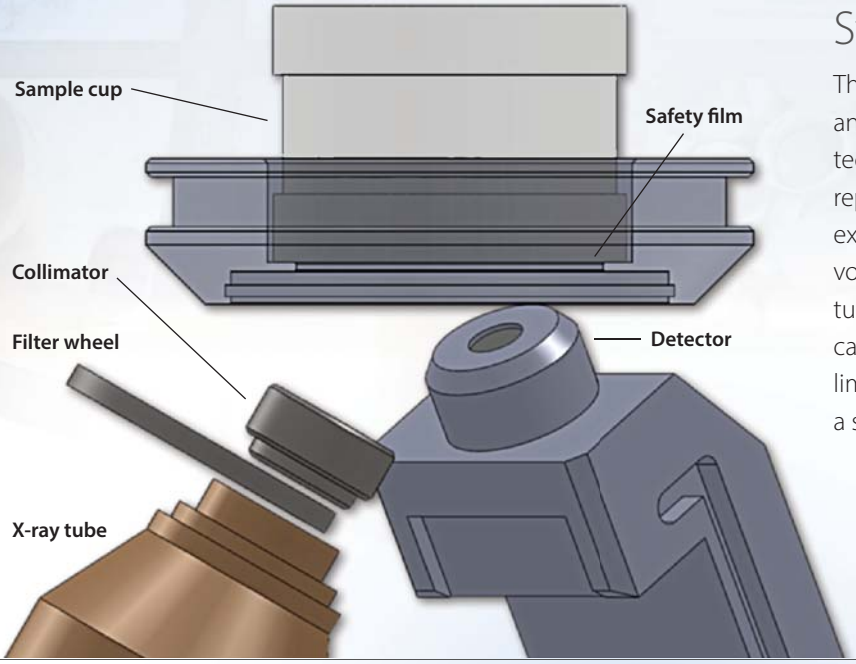
In X-ray fluorescence (XRF), an electron can be ejected from its atomic orbital by the absorption of light (photon) from an X-ray tube. The energy of the photon (hν) must be greater than the energy with which the electron is bound to the nucleus of that atom. When an inner orbital electron is ejected from an atom (middle image), an electron from a higher energy level orbital transfers to fill the vacant orbital. During this transition, a photon may be emitted (right image). Because the energy difference between two specific orbital shells is always the same for a specific element, the emitted photon will always have the same characteristic energy (keV). For a fluorescent emission line, for a given element, the number of photons per unit time (counts per second or cps) is related to the amount of that element in a sample. Counting rates are calculated by measuring, for a set time, the number of photons detected for the various observed elemental X-ray fluorescence lines (spectral peaks). Thus, qualitative and quantitative elemental analysis is achieved by determining the energy of X-ray peaks in a sample spectrum and measuring their associated count rates.



X-ray fluorescence schematic

Computational Dexterity

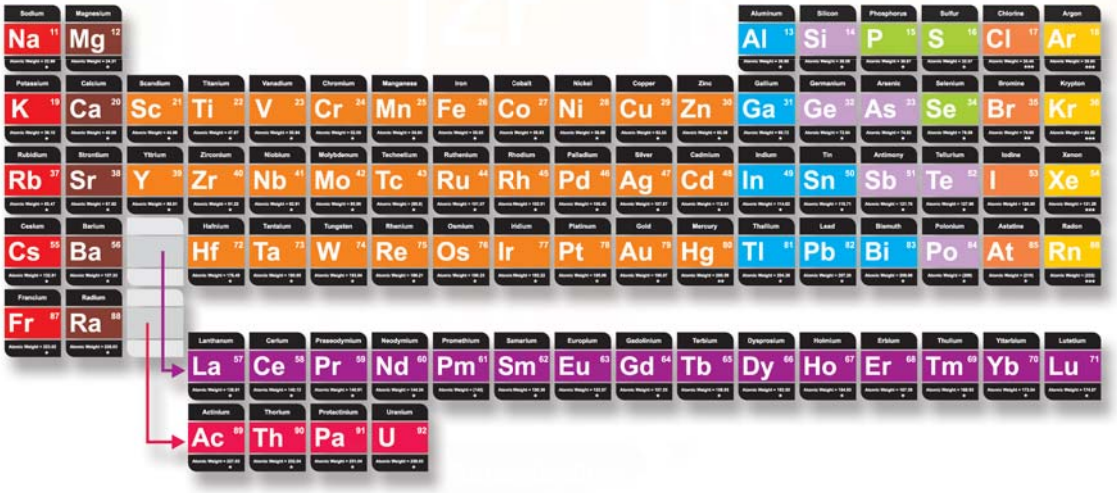
In addition to being remarkably easy to use, each Rigaku NEX QC elemental analyzer is powered by sophisticated software running on an embedded computer. Empirical calibration curves may be linear, quadratic or hyperbolic fits. In addition, to compensate for the presence of other elements, intensity-based or concentration-based alpha (α) corrections may be enabled (automatically calculated given sufficient standards). C/H correction is also available to compensate for light element matrix changes and/or changes in average atomic number. All calibration functions are accessible via intuitive icons at the touch of a finger. An optional fundamental parameters (FP) package is available.



State-of-the-art X-ray Optics

The NEX QC employs a 50 kV X-ray tube, and Peltier cooled semiconductor detector technology to deliver exceptional short-term repeatability and long-term reproducibility with excellent elemental peak resolution. The high voltage, along with multiple automated X-ray tube filters, provides multi-element analysis capability for unmatched performance with low limits-of-detection (LOD). Optics are protected by a safety film that requires no tools to change.

Nondestructively Analyze from Sodium through Uranium



Touchscreen interface

High-resolution, modern, user-friendly touchscreen navigation and instrument control; display interface is "petro pump" quality and hardened for heavy industrial use.

No-tools safety film (to improve readability)

No tools are required to change the safety film protecting the optical kernel, enabling easy and rapid replacement.

Built-in printer

Thermal printer provides fast hard copy results when and where you need them.

X-ray tube conservation

By operating only during data collection, X-ray tube wear and tear is minimized — lowering operating costs.

Fundamental Parameters option

Dramatically reduces the number of standards needed to implement a high quality calibration; especially useful when standards are difficult to obtain or for complex matrices where many elements vary independently.

Up to 38 calibrations

A large number of calibrations are available at the touch of a finger, supporting a vast array of applications and sample types.

Digital data output

Ethernet RJ-45 jack and USB port for output to LIMS or memory stick. Data is available in either CSV or PDF format.

Single position or autosampler

Standard single position configuration can be supplemented with an optional autosampler.

Removable sample trays

Interchangeable optional autosampler trays may be pre-loaded, and swapped in and out, to increase efficiency or where throughput is important. Supports 32 mm and 40 mm cups.

Applications Span Global Industries

Catalysts

EDXRF analysis of heterogeneous and homogeneous catalysts can be used to determine heavy metal content or stoichiometry and/or to quantify poisoning agents. Determination of the value of precious metals content in recycled automotive catalysts is a cost effective application for the NEX QC.

Cement

The Rigaku NEX QC elemental analyzer is a rugged, cost effective solution for quality control measurements at cement plants, making it the ideal tool throughout the production process and as backup to WDXRF systems. NEX QC is applicable to clinker and raw meal, and may be used to measure gypsum (SO_3) in finished cement.

Coatings

Paper and plastic may be coated with a thin layer of silicone as a release coating in the manufacture of tape or other adhesives or as a barrier coating for protection against air in the packaging of food and other materials. Metallic coatings, either electroplated or sputtered onto some substrate material, may also be quantified with NEX QC.

Cosmetics

Since many additives in cosmetics are minerals or inorganic compounds, EDXRF is ideal. Applications include Ti and Zn oxides as UV blockers, as well as Fe, Ti and Zn oxides and metallic dyes as pigments. Rigaku's NEX QC elemental analyzer can also screen cosmetics for toxic metals and inspect incoming raw materials.

Education

An understanding of the basis of atomic spectroscopy is one of the key tenets underpinning the core sciences of physics and chemistry. Low-cost EDXRF is an ideal way to give students instrumentation time in the lab to support their classroom instruction. Unlike AA or ICP, no routine maintenance or consumables are required.

Geology

In studying Earth, geologists routinely analyze the composition of rock and mineral samples. Rapid elemental analyses can be accomplished with the NEX QC elemental analyzer without sample digestion. Common industrial geological applications include analysis of limestone, kaolin clay and silica sand.

Metals and Alloys

Elemental analysis is typically used as a basis for classifying alloys, controlling their production, or verifying their designation. In addition to routine QC applications like iron in aluminum alloys, NEX QC equipped with the VS (variable spot) option may be employed in jewelry analysis to determine composition for valuation.

Mining and refining

Foundries, smelters and mills are characterized by having continuous production, demanding control of both the process and the quality of incoming and outgoing materials. The NEX QC elemental analyzer may be used to analyze ores, feeds, slags and tails. Low-cost EDXRF also makes an ideal backup analyzer.

Paint and pigments

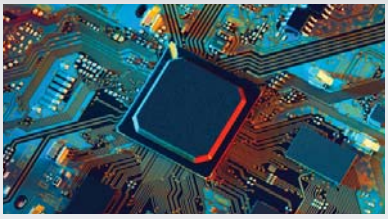
Many paints and pigments contain metal dyes, opacifiers and other inorganic stabilizers that can be analyzed by EDXRF. One specific application is titanium dioxide and lead chromate in white and yellow road paint respectively. NEX QC is the ideal low-cost solution for industrial quality control, as well as for forensic identification of paint chips.

Petroleum

From the quantification of heavy elements in crude oil to sulfur in fuels to a variety of elements in lubricating oils, EDXRF is a well established technique for the petroleum and petrochemical industries. For sulfur in crude oil and bunker fuel, NEX QC is specific to ASTM D4294..

Plastics

Plastics, polymers, and rubber are combined with different additives to afford specific properties. Commonly analyzed as beads, pressed or molded into plaques, typical applications include Br and Sb as fire retardants; stabilizers and lubricants such as P, Ca, Ba, and Zn, as well as Mg, Al, Si, Fe in fiberglass and S in polyurethane.



RoHS

RoHS provides that plastics for consumer goods — as well as new electrical and electronic equipment put on the market for the first time from July 1, 2006 — should not contain certain heavy metal toxins, including: Pb, Cd, Hg, and hexavalent chromium (Cr). NEX QC, with the VS (variable spot) option, can help compliance by providing rapid elemental analysis.

Wood

Processes undertaken to prevent wood rot fall under the definition of wood preservation or timber treatment. The NEX QC can help control a number of different chemical preservatives and processes used to extend the life of wood and engineered wood products, including: CCA, IPBC, PENTA, copper (CA-B, CA-C), and ACZA.

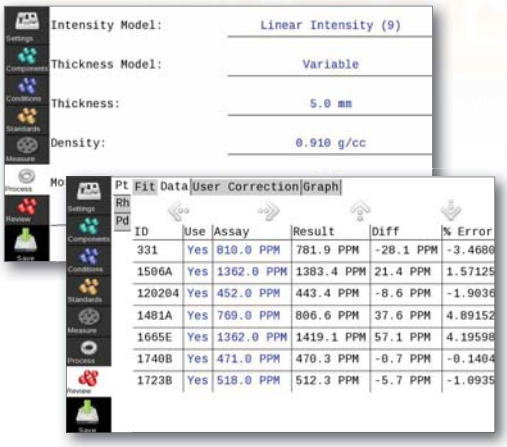
Wovens and non-wovens

Fabrics of all kind are either created with inorganic chemical additives or treated with compounds to modify the behavior of the material. The NEX QC elemental analyzer is ideal for quantifying compounds such as fire retardants, UV stabilizers, anti-microbial treatments and electromagnetic shielding.

Options

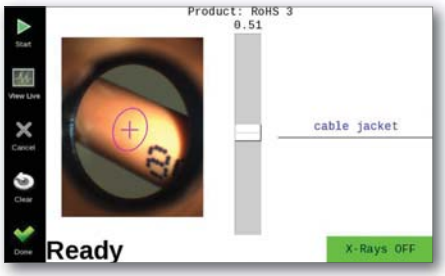
Fundamental Parameters

As an optional means of obtaining semi-quantitative results based on theoretical equations that govern how X-rays interact with matter, fundamental parameters (FP) is a way to determine elemental concentrations without the need for a large suite of standards. In the NEX QC, the sophisticated FP module performs a variety of functions, including: background modeling, spectral deconvolution, peak intensity extraction, and X-ray absorption/enhancement correction. By measuring one or a few assayed type standards (of a specific sample matrix), a Matching Library may be created to improve the theoretical fit. Thus, an FP calibration provides high-quality semi-quantitative concentration results when a large suite of standards is not available.



Variable spot (VS) with CMOS camera

Specifically designed to serve the RoHS and jewelry markets, the variable spot (VS) option features a single-position sample stage with three easily changeable collimators, providing effective analysis spots of 3, 8 and 14 mm. Large irregular objects, as well as small items, are accommodated by the large 190 x 165 x 60 mm sample chamber. A 2.0 megapixel CMOS color camera and LED lighting system allows a sample to be visualized on the touchscreen interface. For complete clarity and optimal sample alignment, the region to be analyzed is marked on the real-time image by a reticle.

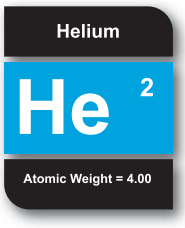


Sample spinner

Coarse grained, inhomogeneous and rough finished samples should be rotated during analysis to provide an averaged presentation and to suppress diffraction peaks. Thus, a single position 32 mm sample spinner is offered as an option. Extremely robust in design, the spinner is almost completely silent while rotating at its nominal speed of 32 rpm. It may be used in autosampler equipped models by replacing the automatic sample tray as needed.

Helium purge

Light element performance is dramatically improved by use of a helium (He) environment during analysis. Helium flow rate is 0.2 liters per minute (SLM).



Autosampler

In addition to the standard single position (32 mm) sample holder (right image) and large object adapter, two automatic sample changers are offered as options. A six position changer (left image) accommodates 32 mm samples while the five position variation accepts 40 mm samples. Both autosampler trays take the respective industry standard XRF sample cups. Extra trays may be used to preload trays for easy batch analysis.

Specifications

General
Energy dispersive X-ray fluorescence (EDXRF)
Analytical range Na to U
PPM to % levels

Excitation
X-ray tube, end window type with Ag anode
50 kV X-ray tube
4 W max power
6 tube filter positions
X-rays only on when analyzing

Detection
High-performance Si-PIN diode detector
Peltier electronic cooling
User configurable shaping times for optimum balance of spectral resolution and count rate

Sample chamber
Large 190 x 165 x 60 mm sample chamber
Single-position 32 mm sample aperture with leak protection
17.5 mm ID flat sample ring for large samples

Environmental conditions
Ambient temperature 10 – 35°C (50 – 95°F)
Relative humidity ≤85% non-condensing
Vibration undetectable by human
Free from corrosive gas, dust and particles

Software
Icon-driven graphical user interface
Simple flow bar wizard to create new applications
Qualitative and quantitative analysis
Single or dual point standardization
6 pre-configured validation schemes with user defined bounds
User-configurable repeat analysis
Live results update
Analysis Complete Remove Sample warning feature
Data export function with LIMS capability
Application method export/import to USB or network folder
Password protection
Multi-language

User Interface
8" WVGA touchscreen interface
Embedded computer
LINUX® operating system
Internal thermal printer
USB and Ethernet connections

Backed by Rigaku

Since its inception in 1951, Rigaku has been at the forefront of analytical and industrial instrumentation technology. With hundreds of major innovations to their credit, the Rigaku group of companies are world leaders in the field of analytical X-ray instrumentation. Rigaku employs over 1,500 people worldwide in operations based in Japan, the U.S., Europe, South America, and China.

Warranty

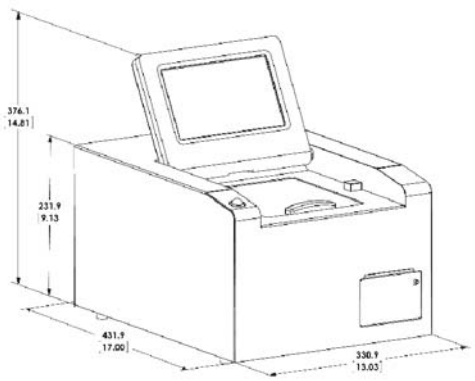
Our Guarantee
Applied Rigaku Technologies offers a 2-year warranty on all EDXRF spectrometers it produces. This industry-leading manufacturer's warranty shows our commitment to quality and displays our dedication to maximizing uptime for our customer's processes and applications.

Options

Helium purge	Flow rate 0.2 L/min (during analysis only) Helium purity 99.95% Tubing 6 mm OD x 4 mm ID, 10 meters
Single-position 40 mm sample aperture	
Single-position 32 mm sample spinner	
6-position automatic sample changer (32 mm samples)	
5-position automatic sample changer (35 – 40 mm samples)	
Uninterruptible power supply (UPS) 865 W / 1500 VA battery backup / transient surge protection	

Spectrometer data

Single phase AC	100 – 240 V, 1.4 A (50/60 Hz)
Dimensions	331 (W) x 432 (D) x 376 (H) mm (13 x 17 x 14.8 in)
Weight	16 kg (35 lbs)



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